

**Search Notes**

Application/Control No.

10/705,818

Examiner

Chuck Huynh

Applicant(s)/Patent under  
Reexamination

NAKAYAMA ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
Updated	Search	1/20/2008	CH
455	411	1/20/2008	CH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/Subclass	1/20/2008	CH
Combined Text Search	1/20/2008	CH
Inventor Search	1/20/2008	CH
Assignee Search	1/20/2008	CH